



Session 6: Combined techniques

Chairman Kevin Sanchez, CNES Toulouse

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| <i>14:30-14:50</i> | Design analysis in analog signal circuits enhanced by Emission Microscopy and laser based techniques (Christof Brillert, INFINEON Munich) |
| <i>14:50-15:10</i> | Failure Diagnosis by Optical Techniques Combined to Layout Localization Software for Wafer Yield Improvement (Lionel Forli, ATMEL Rousset) |
| <i>15:10-15:30</i> | Multiple FA techniques on advanced technologies (Sylvain Dudit, ST Crolles) |
| <i>15:30-15:50</i> | Optical investigation of a resistance-change memory device (Fabio La Matina, EMPA) |
| <i>15:50-16:10</i> | Questions and answers (Franck Zachariasse, NXP, Nijmegen) |